

# PSM20065D

650V 20A 200mΩ Si Super junction MOSFET with Normal body diode

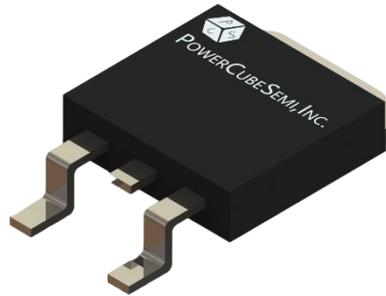
## Features

### Si Super junction MOSFET

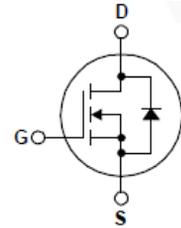
- Rated to 650V at 20Amps @ $T_J = 25^\circ\text{C}$
- Max  $R_{DS(on)} = 200\text{ m}\Omega$
- Typ  $R_{DS(on)} = 190\text{ m}\Omega$
- Gate Charge(Typ.  $Q_g = 35\text{ nC}$ )
- Improved dv/dt Capability
- 100% Avalanche Tested

## Application

- LCD/LED/PDP TV
- Telecom/Server Power supplies
- AC-DC Power Supply
- LED Lighting



PKG type : TO-263 (D2PAK)



## Description

PSM20065D is PowerCubeSemi's second generation of high voltage Super Junction MOSFET that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. Consequently, the combination of Super Junction MOSFET is suitable for various AC/DC power conversion for system miniaturization and higher efficiency

## Absolute Maximum Ratings

Symbol	Parameter	Test Condition	Value	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	650	V
$I_D$	Drain Current	$T_c=25^\circ\text{C}$	20	A
$I_{DM}$	Pulsed Drain Current	Pulse width limited by junction temperature	80	A
$V_{GS}$	Gate-Source Voltage		$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy	$I_{AS}=9A, R_G=25\Omega$ $V_{DD}=50V, L=20mH$	810	mJ
$P_d$	Power Dissipation	$T_c=25^\circ\text{C}$	33	W
$T_J$	Operating Junction Temperature		150	$^\circ\text{C}$
$T_{stg}$	Storage Temperature		-55 to 150	$^\circ\text{C}$



## Package Marking and Ordering Information

Device Marking	Device	Package	Packing Method	Tape width	Quantity
PSM20065D	PSM20065	TO-263 (D2PAK)	-	-	-

## Electrical Characteristics of Si MOSFET

Symbol	Parameter	Test Condition	Numerical			Unit
			Min	Typ.	Max.	
$BV_{DSS}$	Drain-source breakdown voltage	$V_{GS} = 0V, I_D = 250\mu A, T_J = 25^\circ C$	650	-	-	V
$I_{DSS}$	Zero gate voltage drain current	$V_{DS} = 650V, V_{GS} = 0V$	-	-	30	$\mu A$
$I_{GSS}$	Gate-source leakage current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	$\pm 70$	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	3	-	5	V
$R_{DS(ON)}$	Static drain-source on state resistance	$V_{GS} = 10V, I_D = 10A$	-	190	200	m $\Omega$
$t_{d(on)}$	Turn-on Delay time	$V_{DD} = 380V, I_D = 10A, V_{GS} = 10V, R_G = 4.7\Omega$	-	18	-	ns
$T_r$	Turn-on Rise time		-	20	-	
$t_{d(off)}$	Turn-off Delay time		-	64	-	
$T_f$	Turn-off Fall time		-	21	-	



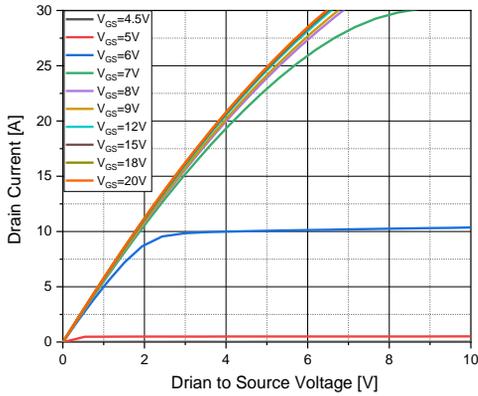
## Electrical Characteristics of Si MOSFET

Symbol	Parameter	Test Condition	Numerical		Unit
			Typ.	Max.	
$R_{\theta JC}$	Thermal resistance, Junction to case		3.77	-	$^{\circ}\text{C}/\text{W}$
$R_g$	Gate resistance	$V_{GS} = 0\text{V}$ , $f = 100\text{kHz}$	4	5	$\Omega$
$C_{iss}$	Input capacitance	$V_{DS} = 380\text{V}$ , $V_{GS} = 0\text{V}$ , $f = 100\text{kHz}$	2000	-	pF
$C_{oss}$	Output capacitance		1500	-	
$C_{rss}$	Reverse transfer capacitance		20	-	
$Q_{g(\text{tot})}$	Total gate charge at 10V	$V_{DS} = 380\text{V}$ , $I_D = 10\text{A}$ $V_{GS(\text{on})} = 10\text{V}$ , $V_{GS(\text{off})} = 0\text{V}$	35	-	nC
$Q_{gs}$	Gate to source gate charge		10	-	
$Q_{gd}$	Gate to drain "Miller" charge		20	-	

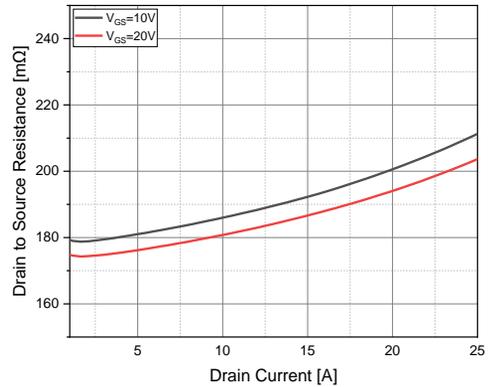
## Electrical Characteristics of Si Diode

Symbol	Parameter	Test Condition	Numerical		Unit
			Typ.	Max.	
$I_S$	Maximum continuous drain to source diode forward current		-	20	A
$I_{SM}$	Maximum pulsed drain to source diode forward current		-	80	A
$V_{SD}$	Drain to source diode forward voltage	$I_{SD} = 10\text{A}$ , $V_{GS} = 0\text{V}$	-	1.1	V
$T_{rr}$	Reverse recovery time	$I_{SD} = 10\text{A}$ , $V_{DD} = 400\text{V}$ , $dI_F/dt = 100\text{A}/\mu\text{s}$	330	-	ns
$Q_{rr}$	Reverse recovery charge		4.8	-	$\mu\text{C}$
$I_{rrm}$	Reverse recovery current		29	-	A

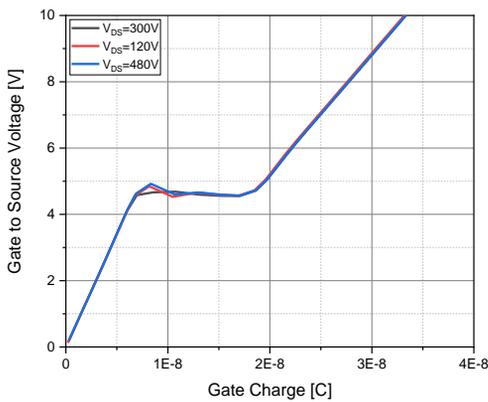
# Typical Characteristics



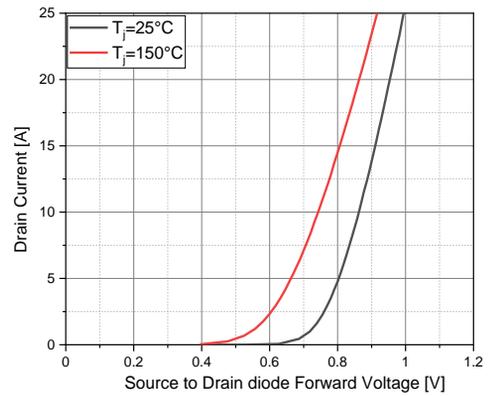
**Figure 1. On-state characteristics**



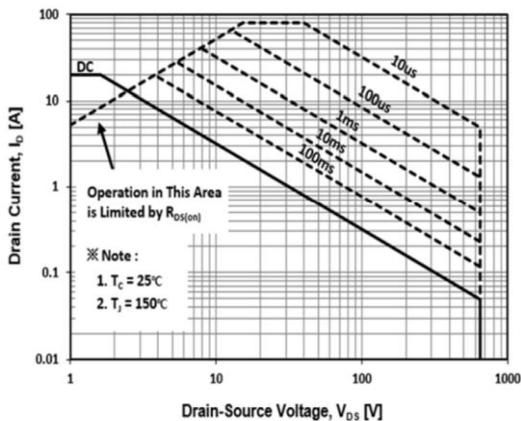
**Figure 2. On resistance variation vs. Drain current and gate voltage**



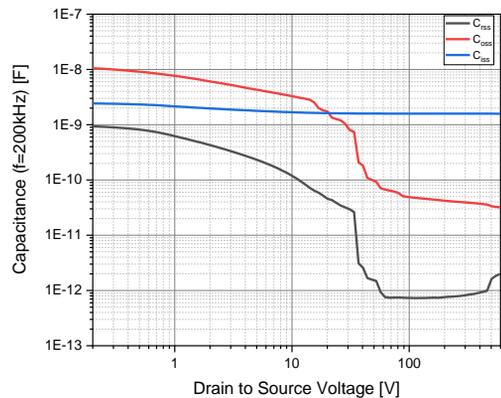
**Figure 3. Gate charge characteristics**



**Figure 4. On-state current vs. Diode forward voltage**

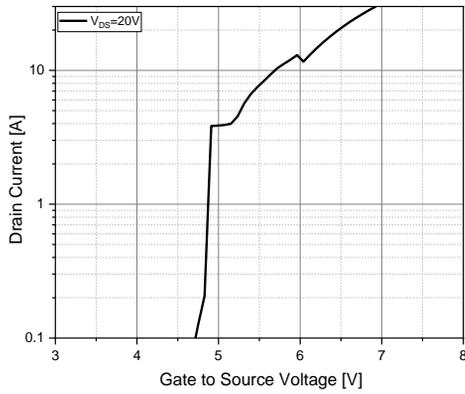


**Figure 5. Maximum safe operating area**

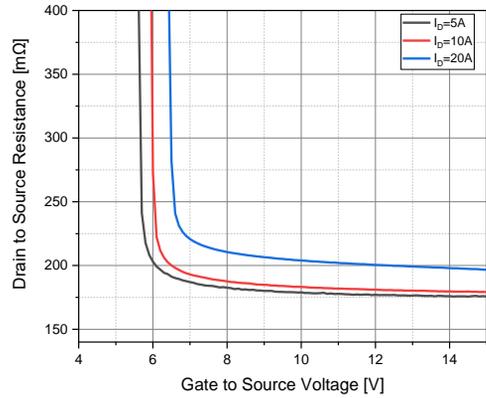


**Figure 6. Capacitance characteristics**

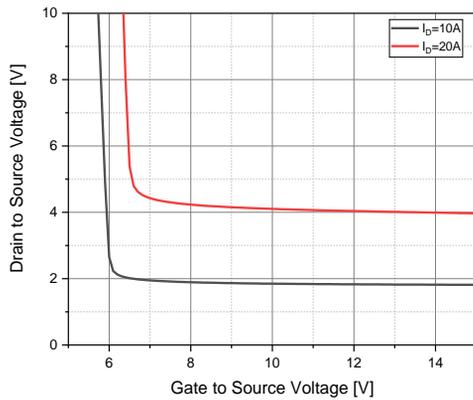
## Typical Characteristics



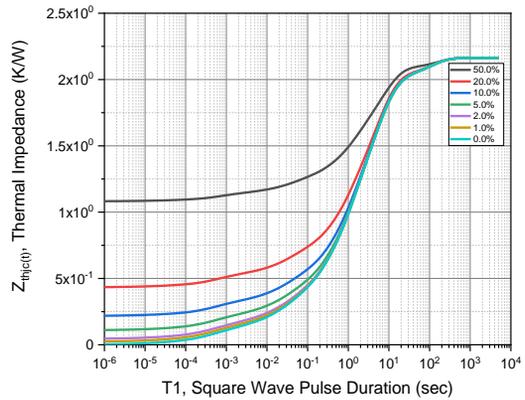
**Figure 7. Transfer characteristics**



**Figure 8. Drain to source resistance vs Gate to source voltage**



**Figure 9. Drain to source voltage vs Gate to source voltage**

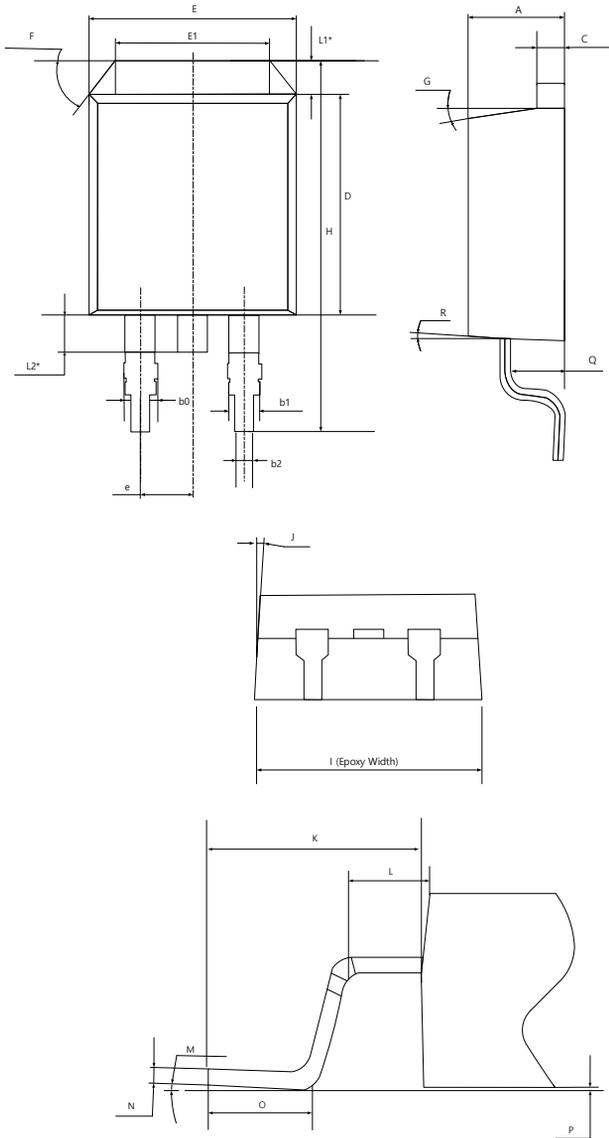


**Figure 10. Transient thermal response curve**



Unit : mm

**Package Outline**



SYMBOL	DIMENSIONS			NOTES
	MIN	NOM	MAX	
<b>A</b>	4.4	4.6	4.8	
<b>b0</b>	1.17	1.37	1.57	
<b>b1</b>	1.17	1.27	1.37	
<b>b2</b>	0.70	0.80	0.90	
<b>C</b>	1.17	1.27	1.37	
<b>D</b>	8.50	8.70	8.90	
<b>E</b>	9.8	10.0	10.2	
<b>E1</b>	6.5	-	-	
<b>e</b>	2.44	2.54	2.64	
<b>F</b>	-	30° (Ref)	-	
<b>G</b>	-	7.0°	-	
<b>H</b>	15.00	15.30	15.60	
<b>I</b>	9.80	10.0	10.20	
<b>J</b>	-	3.0°	-	
<b>K</b>	5.00	5.30	5.60	
<b>L</b>	1.8	2.0	2.2	
<b>L1*</b>	1.07	1.27	1.47	
<b>L2*</b>	1.2	1.5	1.8	
<b>M</b>	0°	-	8°	
<b>N</b>	0.30	0.45	0.60	
<b>O</b>	2.34	2.54	2.74	
<b>P</b>	0	-	0.25	
<b>Q</b>	2.37	2.67	2.97	
<b>R</b>	-	7.0°	-	